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United States Patent [19]

Fukumoto et al.

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[45] **Date of Patent: ** Mar. 21, 1995**

[54] **HARDNESS TESTING APPARATUS**

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[73] Assignee: **Matsuzawa Seiki Kabushikikaisha**, Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **7,935**

[22] Filed: **Apr. 26, 1993**

[30] **Foreign Application Priority Data**

Oct. 26, 1992 [JP] Japan 4-31280

[52] **U.S. Cl.** **D10/75**

[58] **Field of Search** D10/46, 75; 73/78, 79, 73/80, 81, 82, 83, 84; 356/378

[56] **References Cited**

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[57] **CLAIM**

The ornamental design of a hardness testing apparatus, as shown and described.

DESCRIPTION

FIG. **1** is a frontal elevational view showing the new design of the present invention;

FIG. **2** is a top plan view showing the new design of the present invention;

FIG. **3** is a rear elevational view showing the new design of the present invention;

FIG. **4** is a bottom view showing the new design of the present invention;

FIG. **5** is a side view showing the new design of the present invention from the right side relative to the view of FIG. **1**; and,

FIG. **6** is a side view showing the new design of the present invention from the left side relative to the view of FIG. **1**.

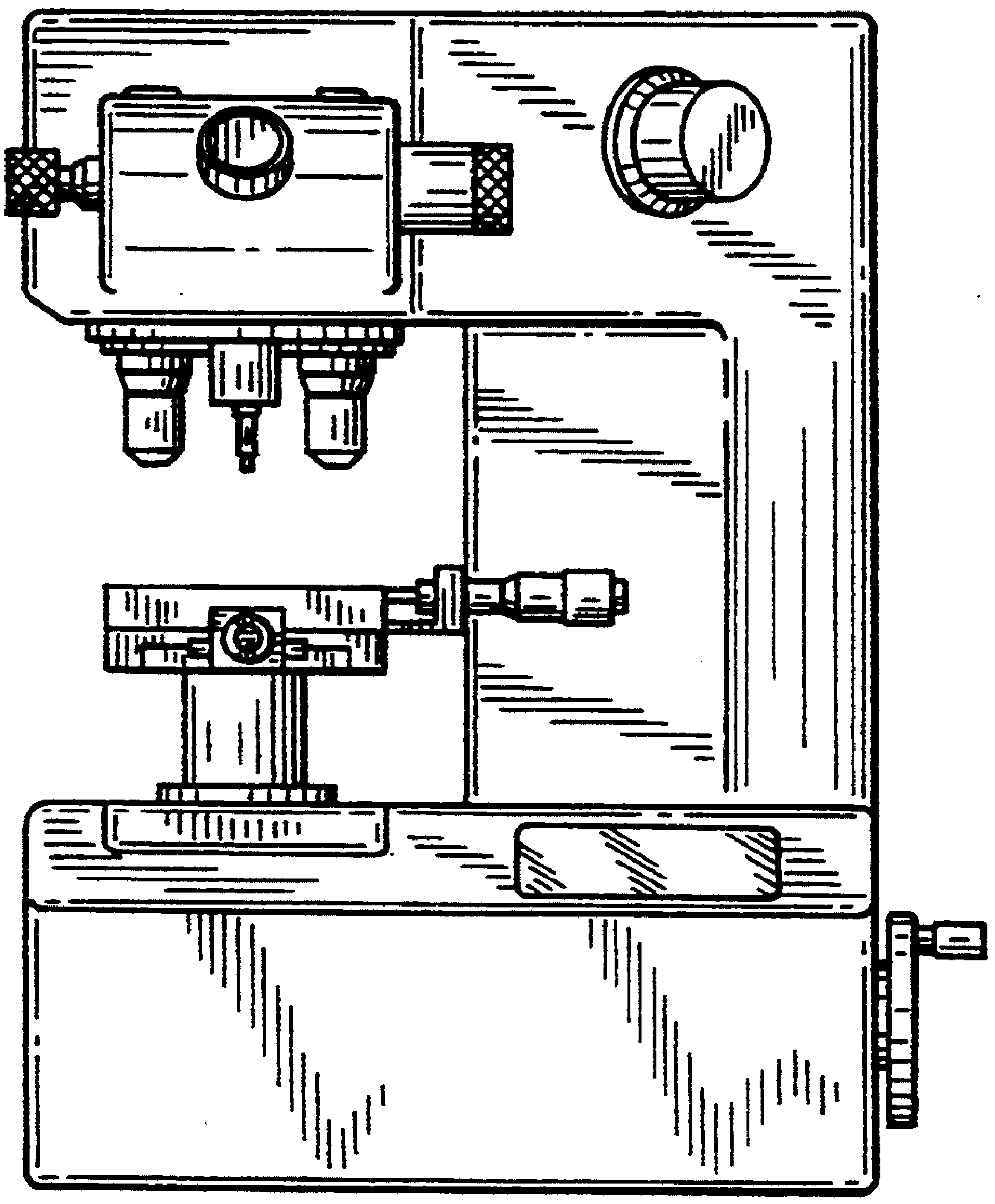


FIG. 1

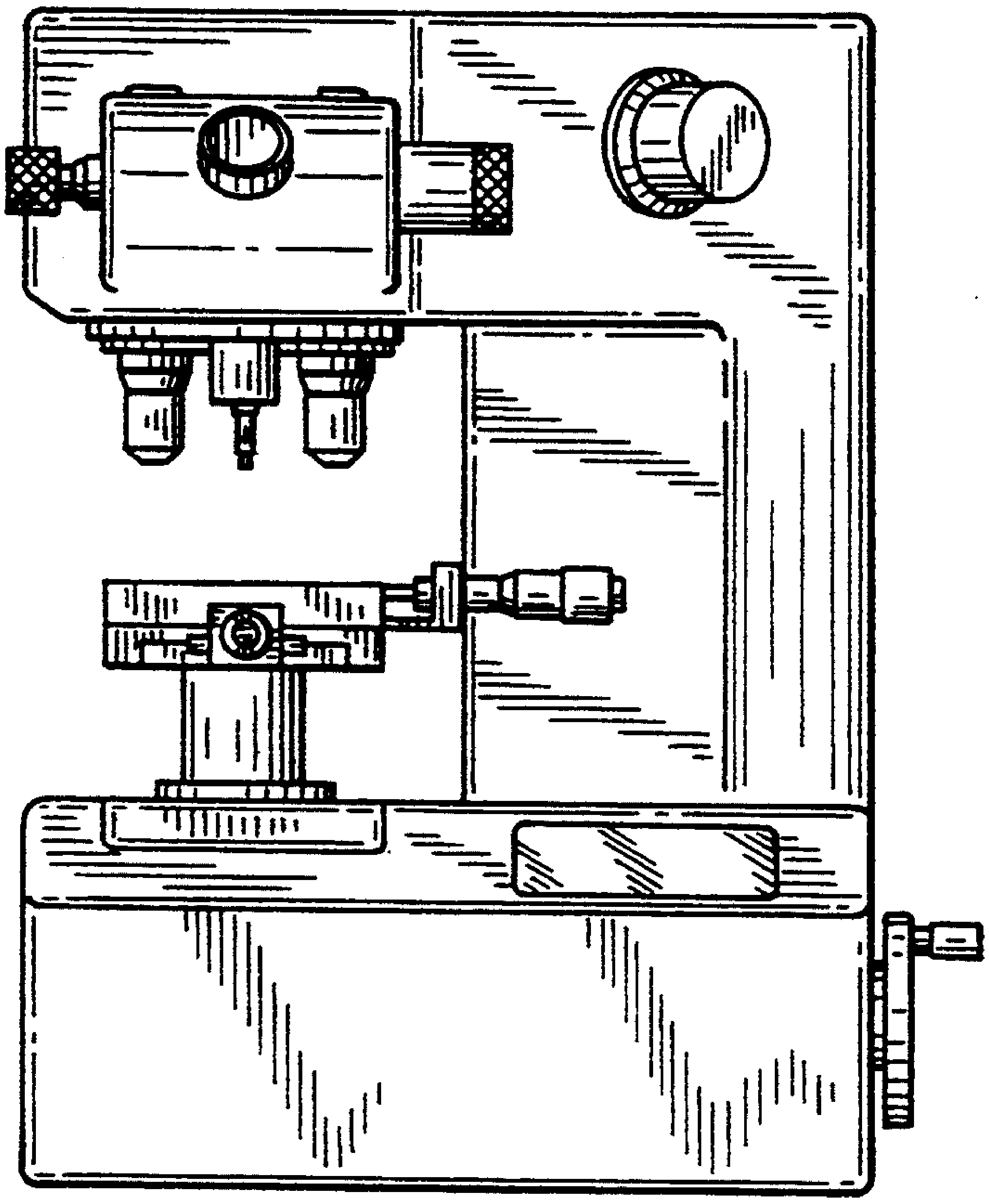


FIG. 2

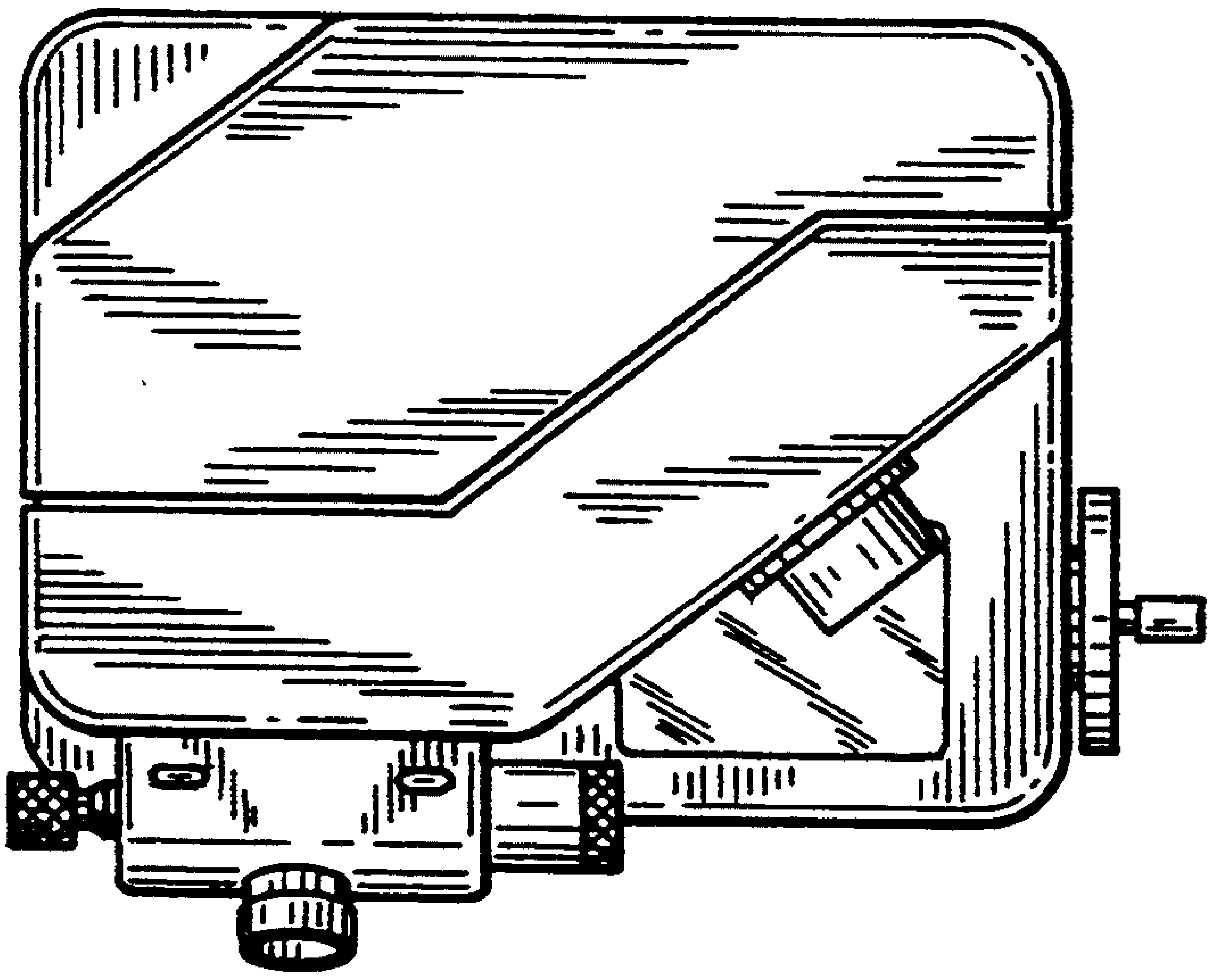


FIG. 3

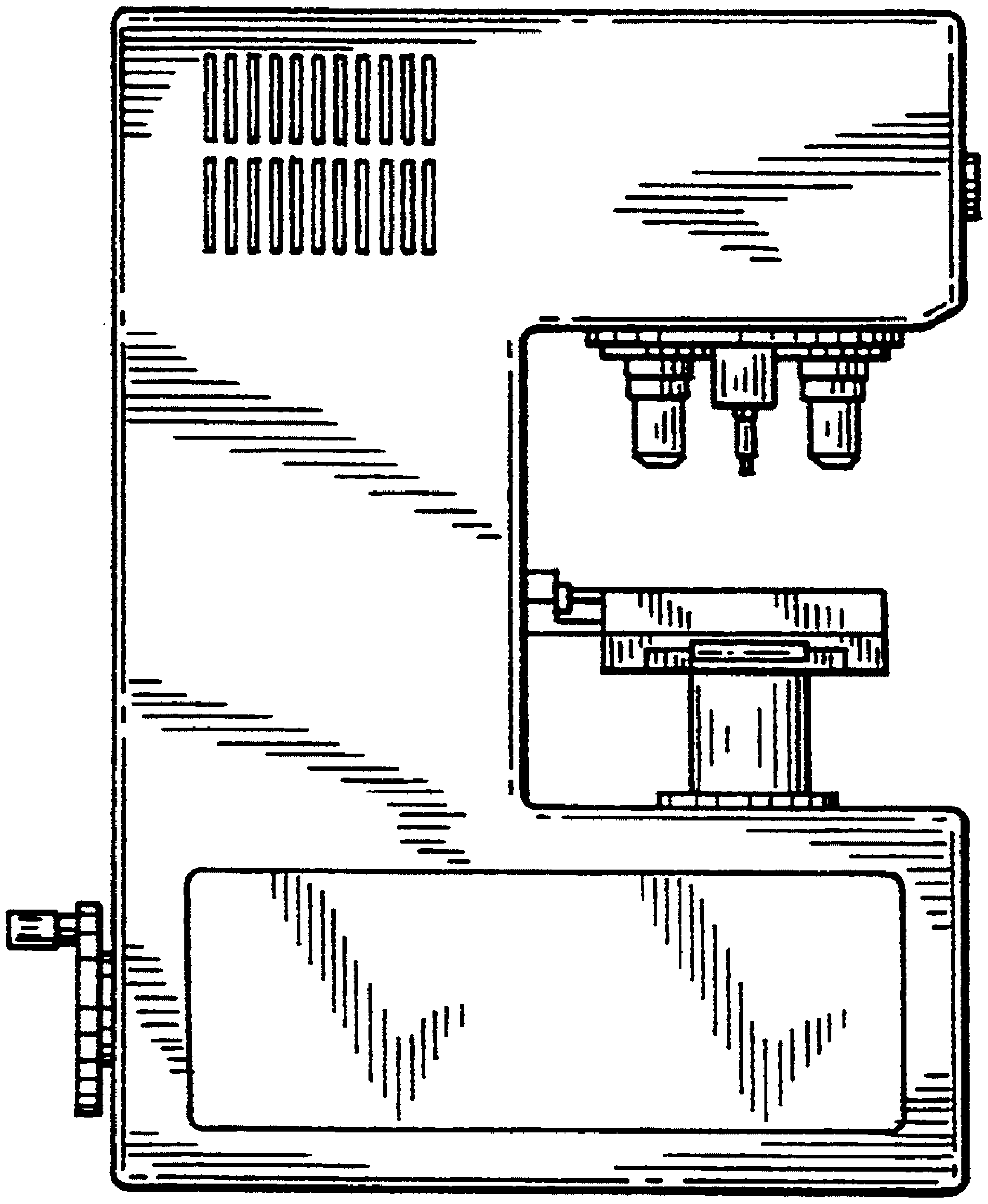
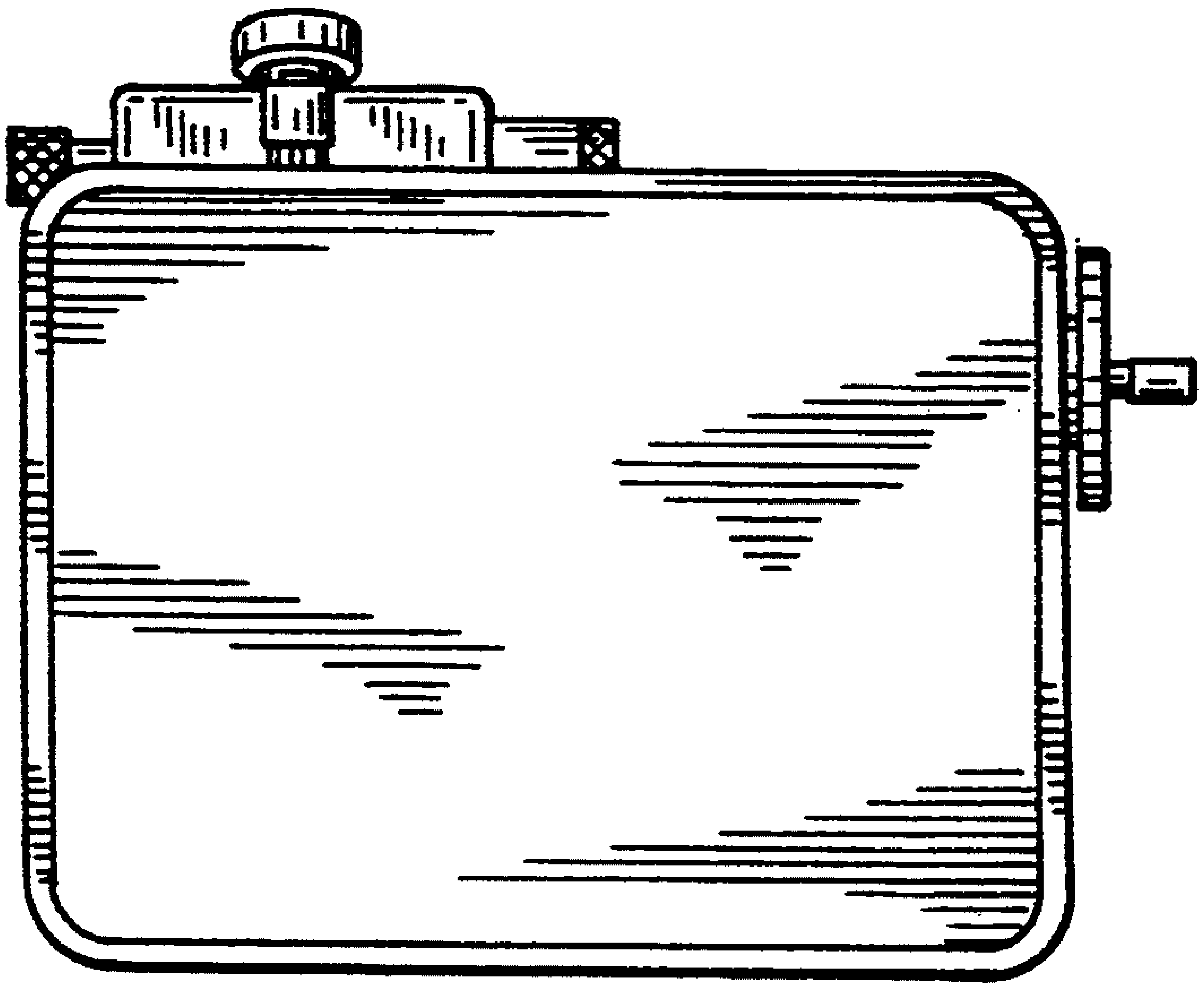


FIG. 4



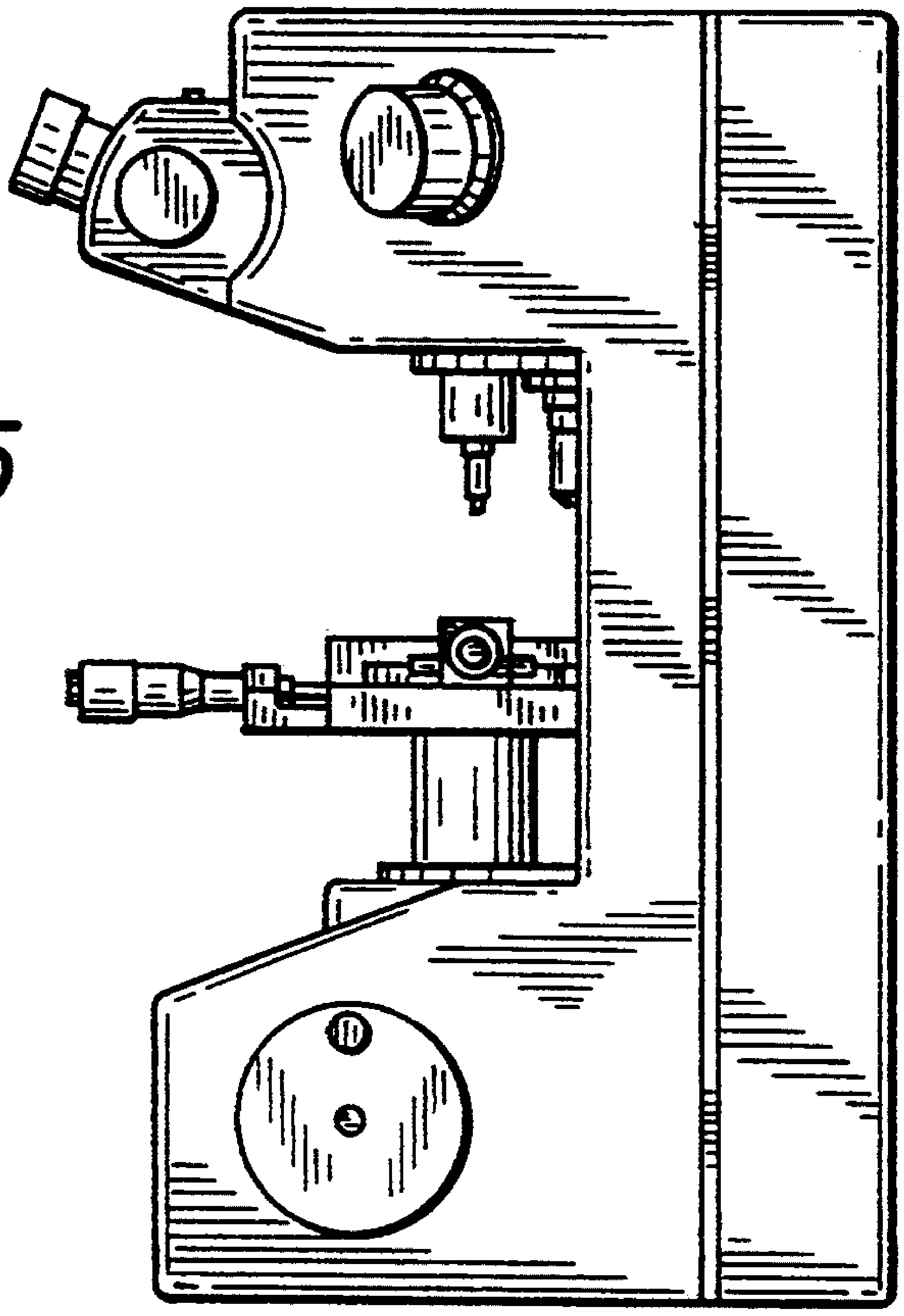


FIG. 5

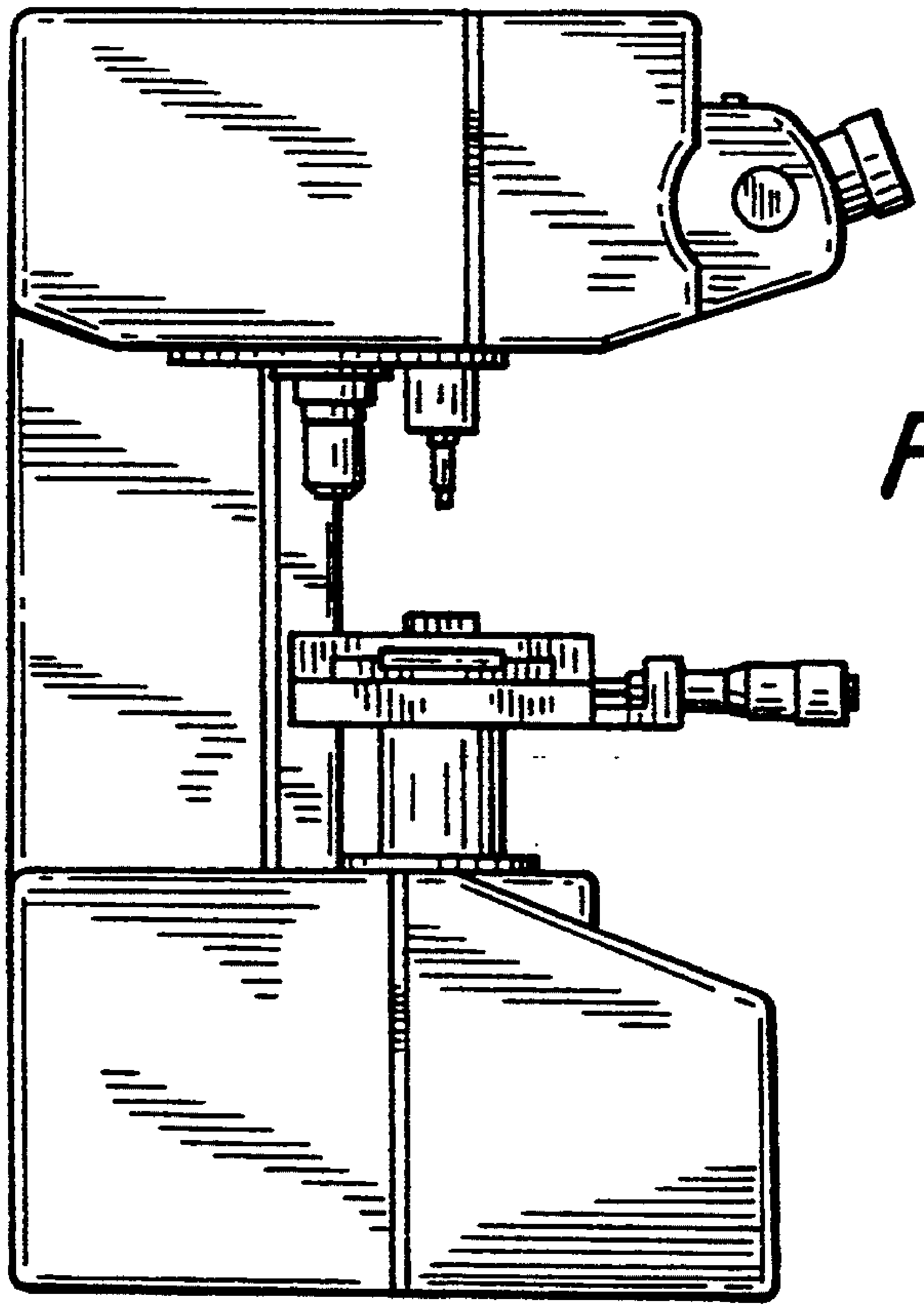


FIG. 6